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David G. Voelz is a professor of electrical engineering at New Mexico State University and holds a Paul W. and Valerie Klipsch Professorship. He received the B.S. degree in electrical engineering from New Mexico State University in 1981 and received the M.S. and Ph.D. degrees in electrical engineering from the University of Illinois in 1983 and 1987, respectively. From 1986 to 2001, he was with the Air Force Research Laboratory in Albuquerque, NM. He was named a Fellow of SPIE in 1999 and has received an OSA

Engineering Excellence Award, the Bromilow Award at NMSU for research excellence, and the Giller Award at AFRL for technical achievement. His research interests always seem to involve some aspect of Fourier optics and include spectral and polarimetric imaging, laser imaging and beam projection, laser communication, adaptive optics, and astronomical instrumentation development.